

DP 650

03.07.2017

Measure Reference	Machine	Recipe	Time (s)	Adh. Layer	Film	Results	+/- %	Substrates	Measurement Tool	number of sites	Date	User
001	DP650	RTF_Cr	294	-	Cr	190 nm	7.5	Float glass	DekTak	5	16.12.2014	bellenrieder
						2.3030 Ω /sq	10.8	Float glass	OmniMap RS-75	5		
						1'963 MPa	-	Si Test	FLX 2320-S	1		
002	DP650	RTU_Cr	345	-	Cr	195 nm	3.1	Float glass	DekTak	5	16.12.2014	bellenrieder
						3.2700 Ω /sq	5.6	Float glass	OmniMap RS-75	5		
						1'268 MPa	-	Si Test	FLX 2320-S	1		
003	DP650	RTU_Cr	862	-	Cr	487 nm	-	-	-	-	16.12.2014	bellenrieder
						- Ω /sq	-	-	-	-		
						860 MPa	-	Si Test	FLX 2320-S	1		
004	DP650	RTU_Cr	862	-	Cr	487 nm	-	-	-	-	16.12.2014	bellenrieder
						- Ω /sq	-	-	-	-		
						852 MPa	-	Si Test + wox	FLX 2320-S	1		
005	DP650	RT_E_Cr_unif	862	-	Cr	487 nm	-	-	-	-	16.12.2014	bellenrieder
						- Ω /sq	-	-	-	-		
						822 MPa	-	Si Test + wox	FLX 2320-S	1		
006	DP650	RTU_Cr-Cu	156	Cr 10nm	Cu	197 nm	8.2	Float glass	DekTak	5	03.02.2015	bellenrieder
						0.1328 Ω /sq	8.8	Float glass	OmniMap RS-75	5		
						231 MPa	0.9	Si Test	FLX 2320-S	2		
007	DP650	RTF_Cr-Cu	77	Cr 10nm	Cu	202 nm	10.4	Float glass	DekTak	5	03.02.2015	bellenrieder
						0.1305 Ω /sq	13.6	Float glass	OmniMap RS-75	5		
						258 MPa	0.1	Si Test	FLX 2320-S	2		
008	DP650	RTU_Ta	667	-	Ta	199 nm	3.5	Float glass	DekTak	5	03.02.2015	bellenrieder
						8.9007 Ω /sq	6.2	Float glass	OmniMap RS-75	5		
						-1'305 MPa	0.1	Si Test	FLX 2320-S	2		
009	DP650	RTF_Ta	333	-	Ta	202 nm	5.2	Float glass	DekTak	5	03.02.2015	bellenrieder
						8.7923 Ω /sq	8.3	Float glass	OmniMap RS-75	5		
						-1'550 MPa	0.1	Si Test	FLX 2320-S	2		
010	DP650	RTU_Ta(LS)	667	-	Ta	-35 MPa	37.0	Si Test	FLX 2320-S	2	19.02.2015	bellenrieder
011	DP650	RTU_Cr-Al	339	Cr 10nm	Al	179 nm	7.8	Float glass	DekTak	5	25.02.2015	bellenrieder
						0.2727 Ω /sq	11.4	Float glass	OmniMap RS-75	5		
						31 MPa	9.2	Si Test	FLX 2320-S	2		
012	DP650	RTF_Cr-Al	145	Cr 10nm	Al	176 nm	16.8	Float glass	DekTak	5	25.02.2015	bellenrieder
						0.2147 Ω /sq	19.1	Float glass	OmniMap RS-75	5		
						68 MPa	26.9	Si Test	FLX 2320-S	2		
013	DP650	RTU_Cr-Au	175	Cr 10nm	Au	217 nm	10.3	Float glass	DekTak	5	02.03.2015	bellenrieder
						0.2362 Ω /sq	12.2	Float glass	OmniMap RS-75	5		
						85 MPa	10.3	Si Test	FLX 2320-S	2		

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014	DP650	RTF_Cr-Au	102	Cr 10nm	Au	195 nm	16.1	Float glass	DekTak	5	23.02.2015	bellenrieder
						0.2631 Ω /sq	16.8	Float glass	OmniMap RS-75	5		
						78 MPa	1.0	Si Test	FLX 2320-S	2		
015	DP650	RTU_Cr-Ni	556	Cr 10nm	Ni	210 nm	9.6	Float glass	DekTak	5	23.02.2015	bellenrieder
						0.4806 Ω /sq	9.3	Float glass	OmniMap RS-75	5		
						398 MPa	1.3	Si Test	FLX 2320-S	2		
016	DP650	RTF_Cr-Ni	250	Cr 10nm	Ni	202 nm	16.3	Float glass	DekTak	5	04.03.2015	bellenrieder
						0.5336 Ω /sq	18.4	Float glass	OmniMap RS-75	5		
						201 MPa	0.5	Si Test	FLX 2320-S	2		
017	DP650	RTU_Cr-Pt	286	Cr 10nm	Pt	192 nm	6.9	Float glass	DekTak	5	04.03.2015	bellenrieder
						0.8921 Ω /sq	6.5	Float glass	OmniMap RS-75	5		
						-463 MPa	0.3	Si Test	FLX 2320-S	2		
018	DP650	RTF_Cr-Pt	194	Cr 10nm	Pt	209 nm	16.4	Float glass	DekTak	5	04.03.2015	bellenrieder
						0.8242 Ω /sq	15.0	Float glass	OmniMap RS-75	5		
						-423 MPa	0.1	Si Test	FLX 2320-S	2		
019	DP650	RTU_Si	1111	-	Si	203 nm	9.3	Si Test + wox	Sopra GES 5E	5	23.02.2015	bellenrieder planglet
						52 MPa	4.8	Si Test	FLX 2320-S	2		
020	DP650	RTU_Ti	488	-	Ti	153 nm	6.4	Float glass	DekTak	5	02.03.2015	bellenrieder
						5.2085 Ω /sq	7.1	Float glass	OmniMap RS-75	5		
						-103 MPa	5.5	Si Test	FLX 2320-S	2		
021	DP650	RTF_Ti	256	-	Ti	160 nm	9.2	Float glass	DekTak	5	02.03.2015	bellenrieder
						3.9258 Ω /sq	10.1	Float glass	OmniMap RS-75	5		
						-660 MPa	0.2	Si Test	FLX 2320-S	2		
022	DP650	RTU_Cr	17	-	Cr	10 nm					30.03.2015	bellenrieder
						3'025 MPa	1.2	Si Test	FLX 2320-S	2		
023	DP650	RTF_Cr	15	-	Cr	10 nm					30.03.2015	bellenrieder
						3'246 MPa	2.0	Si Test	FLX 2320-S	2		
024	DP650	RTU_Cr-Ag	111	Cr 10nm	Ag	202 nm	8.2	Float glass	DekTak	5	20.04.2015	bellenrieder
						0.1355 Ω /sq	9.2	Float glass	OmniMap RS-75	5		
						14 MPa	13.5	Si Test	FLX 2320-S	2		
025	DP650	RTF_Cr-Ag	69	Cr 10nm	Ag	206 nm	14.8	Float glass	DekTak	5	20.04.2015	bellenrieder
						0.1362 Ω /sq	17.2	Float glass	OmniMap RS-75	5		
						32 MPa	8.9	Si Test	FLX 2320-S	2		
026	DP650	RTU_Cr-Ir	465	Cr 10nm	Ir	195 nm	7.8	Float glass	DekTak	5	11.05.2015	bellenrieder
						0.9205 Ω /sq	9.5	Float glass	OmniMap RS-75	5		
						-1'926 MPa	6.7	Si Test	FLX 2320-S	2		

DP 650

03.07.2017

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027	DP650	RTF_Cr-Ir	227	Cr 10nm	Ir	192 nm	7.8	Float glass	DekTak	5	11.05.2015	bellenrieder
						0.9316 Ω/sq	9.5	Float glass	OmniMap RS-75	5		
						-1'750 MPa	0.3	Si Test	FLX 2320-S	2		
028	DP650	RTU_IrOx	267	-	IrOx	174 nm	4.4	Float glass	DekTak	5	11.05.2015	bellenrieder
						22.7100 Ω/sq	10.4	Float glass	OmniMap RS-75	5		
						-2'066 MPa	0.1	Si Test	FLX 2320-S	2		
029	DP650	RTU_Cr-Ta	667	Cr 10nm	Ta	202 nm	7.6	Float glass	DekTak	5	30.03.2015	bellenrieder
						2.2740 Ω/sq	18.0	Float glass	OmniMap RS-75	5		
						-1'506 MPa	1.6	Si Test	FLX 2320-S	2		
030	DP650	RTF_Cr-Ta	328	Cr 10nm	Ta	199 nm	7.6	Float glass	DekTak	5	30.03.2015	bellenrieder
						1.1670 Ω/sq	18.0	Float glass	OmniMap RS-75	5		
						-1'714 MPa	1.6	Si Test	FLX 2320-S	2		
031	DP650	RTU_Cr-Ta(LS)	667	Cr 10nm	Ta	359 nm	8.5	Float glass	DekTak	5	11.05.2015	bellenrieder
						28.1300 Ω/sq	19.8	Float glass	OmniMap RS-75	5		
						-94 MPa	2.8	Si Test	FLX 2320-S	2		
032	DP650	RTU_Cr-Pd	208	Cr 10nm	Pd	217 nm	6.2	Float glass	DekTak	5	27.04.2015	bellenrieder
						0.7103 Ω/sq	6.2	Float glass	OmniMap RS-75	5		
						-37 MPa	0.7	Si Test	FLX 2320-S	2		
033	DP650	RTF_Cr-Pd	126	Cr 10nm	Pd	218 nm	11.1	Float glass	DekTak	5	27.04.2015	bellenrieder
						0.6769 Ω/sq	14.3	Float glass	OmniMap RS-75	5		
						-47 MPa	7.1	Si Test	FLX 2320-S	2		
034	DP650	RTU_Cr-Mo	313	Cr 10nm	Mo	218 nm	3.9	Float glass	DekTak	5	27.04.2015	bellenrieder
						0.7094 Ω/sq	12.6	Float glass	OmniMap RS-75	5		
						470 MPa	0.7	Si Test	FLX 2320-S	2		
035	DP650	RTF_Cr-Mo	150	Cr 10nm	Mo	214 nm	10.8	Float glass	DekTak	5	27.04.2015	bellenrieder
						0.6333 Ω/sq	15.6	Float glass	OmniMap RS-75	5		
						-448 MPa	0.7	Si Test	FLX 2320-S	2		
036	DP650	RTU_Cr-W		Cr 10nm	W	nm		Float glass	DekTak	5	20.04.2015	bellenrieder
						Ω/sq		Float glass	OmniMap RS-75	5		
						-2'206 MPa	0.3	Si Test	FLX 2320-S	2		
037	DP650	RTF_Cr-W		Cr 10nm	W	nm		Float glass	DekTak	5	20.04.2015	bellenrieder
						Ω/sq		Float glass	OmniMap RS-75	5		
						-2'596 MPa	0.2	Si Test	FLX 2320-S	2		
038	DP650	RTU_Cr-WTi10%	606	Cr 10nm	WTi10%	214 nm	5.3	Float glass	DekTak	5	20.04.2015	bellenrieder
						3.1370 Ω/sq	6.6	Float glass	OmniMap RS-75	5		
						-2'283 MPa	8.0	Si Test	FLX 2320-S	2		
039	DP650	RTF_Cr-WTi10%	294	Cr 10nm	WTi10%	214 nm	9.8	Float glass	DekTak	5	20.04.2015	bellenrieder
						3.0960 Ω/sq	12.8	Float glass	OmniMap RS-75	5		
						-2'171 MPa	0.3	Si Test	FLX 2320-S	2		

DP 650

03.07.2017

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040	DP650	RTU_Cr-WTi10%(LS)	606	Cr 10nm	WTi10%	411 nm	7.7	Float glass	DekTak	5	20.04.2015	bellenrieder
						28.4000 Ω/sq	16.6	Float glass	OmniMap RS-75	5		
						-69 MPa	2.2	Si Test	FLX 2320-S	2		
041	DP650	RTF_Cr-WTi10%(LS)	294	Cr 10nm	WTi10%	353 nm	9.6	Float glass	DekTak	5	20.04.2015	bellenrieder
						6.6820 Ω/sq	25.6	Float glass	OmniMap RS-75	5		
						96 MPa	3.0	Si Test	FLX 2320-S	2		
042	DP650	RTU_Cr-Sn	60	Cr 10nm	Sn	218 nm	7.8	Float glass	DekTak	5	24.06.2015	gclerc planglet
						4.5830 Ω/sq	18.4	Float glass	OmniMap RS-75	5		
						-33 MPa	5.6	Si Test	FLX 2320-S	2		
043	DP650	RTF_Cr-Sn	60	Cr 10nm	Sn	325 nm	7.8	Float glass	DekTak	5	24.06.2015	gclerc planglet
						0.6914 Ω/sq	21.6	Float glass	OmniMap RS-75	5		
						9 MPa	7.6	Si Test	FLX 2320-S	2		
044	DP650	RTU_WOx	300	-	WOx	152 nm Ω/sq MPa	8.2	Si Test	Sopra GES 5E	5	29.07.2015	planglet
045	DP650	RTU_WOx	300	-	WOx	154 nm	8.1	Si Test	Sopra GES 5E	5	30.07.2015	planglet
						Ω/sq	3.9	Si Test	FLX 2320-S	2		
046	DP650	RTU_W(LS)	400	-	W	144 nm	9.9	Float glass	DekTak	5	02.05.2016	planglet
						1.4460 Ω/sq	7.2	Float glass	OmniMap RS-75	5		
						-1'327 MPa	0.9	Si Test	FLX 2320-S	2		
047	DP650	RTU_Cr-IrOx(LS)	300	-	IrOx	238 nm	4.4	Float glass	DekTak	5	20.06.2016	gclerc planglet
						Ω/sq	0.7	Si Test	FLX 2320-S	2		
048	DP650	RTU_Cu3N	600	-	Cu3N	275 nm	7.2	Float glass	DekTak	5	05.10.2016	gclerc planglet
						Ω/sq						
049	DP650		600	-	FeCoB	17.5 nm					28.11.2016	kbaumgärtl
						Ω/sq						
050	DP650	RTU_Cr-Sb	180	Cr 10nm	Sb	491.4 nm		Float glass	DekTak	2	11.05.2017	gclerc planglet
						Ω/sq		Float glass	OmniMap RS-75			
051	DP650	RTF_Cr-Sb	180	Cr 11nm	Sb	1'077.0 nm		Float glass	DekTak	2	11.05.2017	gclerc planglet
						Ω/sq		Float glass	OmniMap RS-75			
052	DP650	RTS_Sb	600	-	Sb	200.0 nm		Si Test	DekTak	1	07.06.2017	promero
						Ω/sq						
						MPa						

DP 650

03.07.2017

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053	DP650	RTS_Cu	100	-	Cu	13.2 nm Ω/sq MPa		Si Test	XRR XRD Empyrean Diffractometer	1	26.06.2017	mblank